

# P-Channel 30-V (D-S) MOSFET

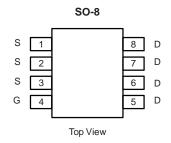
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>d</sup>	Q <sub>g</sub> (Typ.)		
- 30	0.018 at V <sub>GS</sub> = - 10 V	- 9.0	13 nC		
- 30	0.024 at $V_{GS}$ = - 4.5 V	- 7.8	13110		

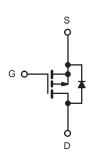
#### **FEATURES**

- Halogen-free According to IEC 61249-2-21
  Definition
- TrenchFET<sup>®</sup> Power MOSFET
- 100 % Rg Tested

#### **APPLICATIONS**

- Load Switch
- Battery Switch





P-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> $T_A = 25 \text{ °C}$ , unless otherwise noted						
Parameter	Symbol	Limit	Unit			
Drain-Source Voltage	V <sub>DS</sub>	- 30	V			
Gate-Source Voltage	V <sub>GS</sub>	± 20	v			
	T <sub>C</sub> = 25 °C		- 9.0			
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>C</sub> = 70 °C		- 7.2			
Continuous Drain Current $(1) = 150^{\circ}$ C)	T <sub>A</sub> = 25 °C		- 7.0 <sup>a, b</sup>			
	T <sub>A</sub> = 70 °C		- 5.6 <sup>a, b</sup>	A		
Pulsed Drain Current	I <sub>DM</sub>	- 30				
Continuous Source Droin Diado Current	T <sub>C</sub> = 25 °C	L.	- 3.5			
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	Is –	- 2.1 <sup>a, b</sup>			
	T <sub>C</sub> = 25 °C		4.2			
Maximum Dawar Dissingtion	T <sub>C</sub> = 70 °C		2.7	w		
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub> —	2.5 <sup>a, b</sup>	VV		
	T <sub>A</sub> = 70 °C	1	1.6 <sup>a, b</sup>			
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C			

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>a, c</sup>	t ≤ 10 s	R <sub>thJA</sub>	40	50	°C/W
Maximum Junction-to-Foot	Steady State	R <sub>thJF</sub>	24	30	0,000

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. t = 10 s.

c. Maximum under Steady State conditions is 95 °C/W.

d. Based on  $T_C = 25 \text{ °C}$ .

HALOGEN

Available

<b>B</b> <sup>®</sup> VBsemi
www.VBsemi.com

<b>SPECIFICATIONS</b> T <sub>J</sub> = 25 °C, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static			- 30				
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = -250 \mu\text{A}$				V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 31		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			4.5			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	- 1.0		- 2.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55 \text{ °C}$			- 1 - 5	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \le -5 V$ , $V_{GS} = -10 V$	- 20			Α	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = -10 \text{ V}, \text{ I}_{D} = -7.0 \text{ A}$ $V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -5.6 \text{ A}$		0.018		Ω	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 7.0 A		18		S	
Dynamic <sup>b</sup>	010						
Input Capacitance	C <sub>iss</sub>			1455			
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz		180		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			145		- <sup></sup>	
Total Gate Charge		V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 7.0 A		25	38		
	Qg	$Q_g$		13	20		
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ = - 15 V, $V_{GS}$ = - 4.5 V, $I_{D}$ = - 7.0 A		3.5	-	nC	
Gate-Drain Charge	Q <sub>gd</sub>			5.5			
Gate Resistance	R <sub>q</sub>	f = 1 MHz	0.4	2.0	4.0	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			10	20		
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 15 V, R <sub>L</sub> = 2.7 $\Omega$		13	20		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong$ - 5.6 A, $V_{GEN}$ = - 10 V, $R_a$ = 1 $\Omega$		23	35		
Fall Time	t <sub>f</sub>	5		9	18		
Turn-On Delay Time	t <sub>d(on)</sub>			38	57	ns	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 15 V, R <sub>L</sub> = 2.7 $\Omega$		89	134	-	
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong -5.6 \text{ A}, \text{ V}_{\text{GEN}} = -4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		22	33		
Fall Time	t <sub>f</sub>	- <b>3</b>		11	17		
Drain-Source Body Diode Characteris				I			
Continous Source-Drain Diode Current	۱ <sub>S</sub>	T <sub>C</sub> = 25 °C			- 6.5	Ι.	
Pulse Diode Forward Current	I <sub>SM</sub>	-			- 30	A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 5.6 A, V <sub>GS</sub> = 0 V		- 0.71	- 1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			22	33	ns	
Body Diode Reverse Recovery Charge	Reverse Recovery Charge $Q_{rr}$ $I_r = -5.6 \text{ A}$ , $dl/dt = 100 \text{ A/us}$ , $T_1 = 2$			17	26	nC	
Reverse Recovery Fall Time				13			
Reverse Recovery Rise Time	t <sub>b</sub>	4 F		9		ns	

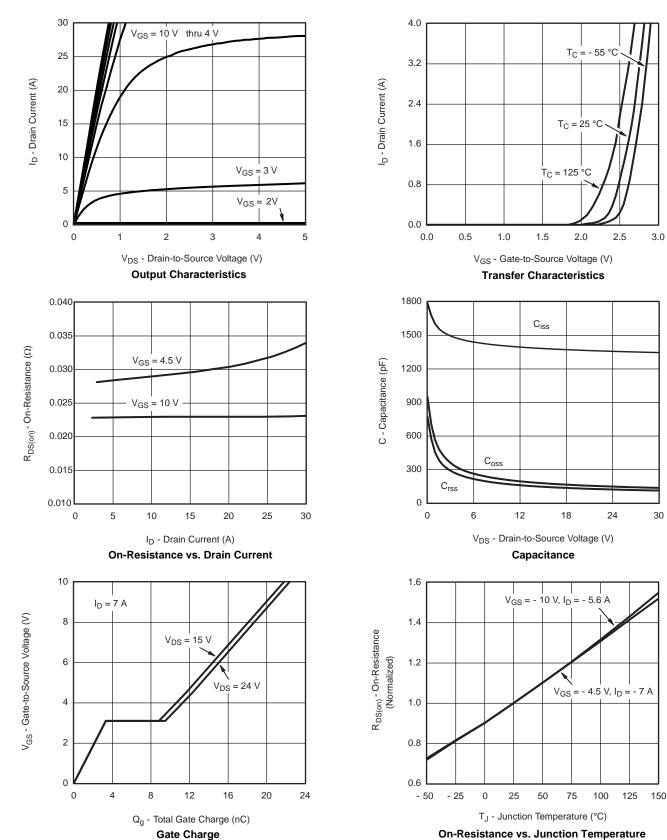
Notes:

a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.

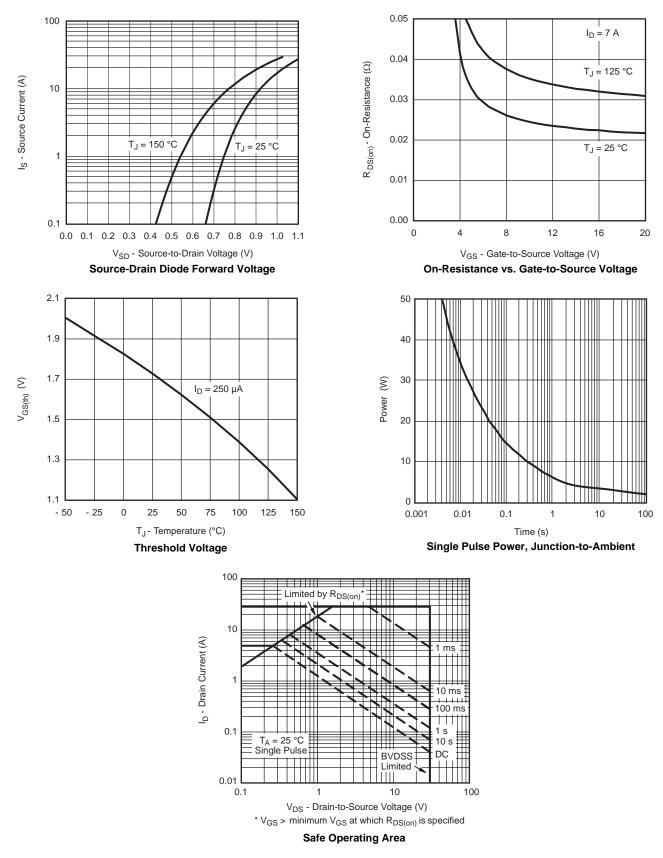
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

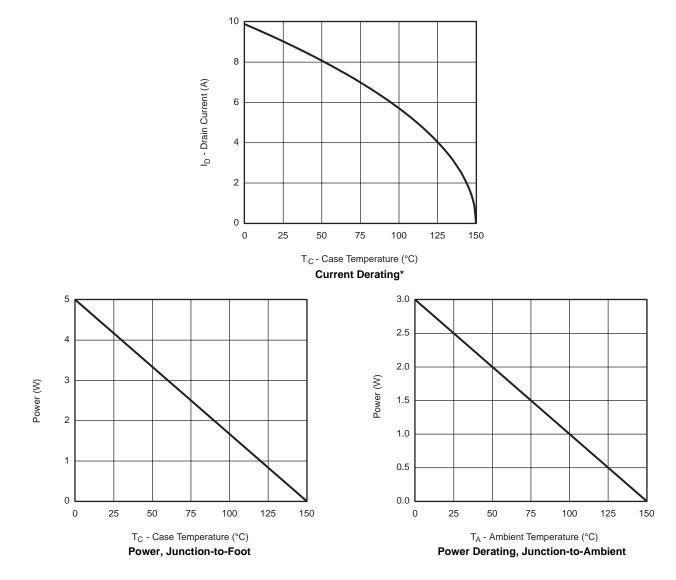






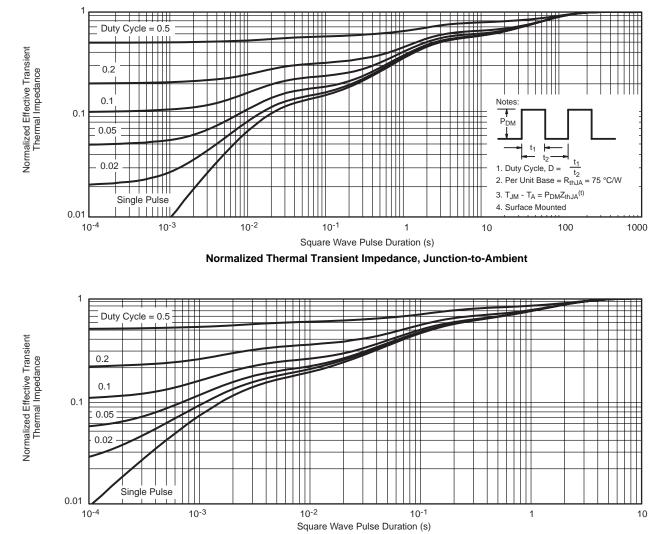






\* The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Foot



## SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012





	MILLIMETERS		INC	HES		
DIM	Min	Max	Min	Max		
A	1.35	1.75	0.053	0.069		
A <sub>1</sub>	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
e	1.27 BSC		0.050	) BSC		
н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498						



**RECOMMENDED MINIMUM PADS FOR SO-8** 



Recommended Minimum Pads Dimensions in Inches/(mm)



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